



SHENZHEN LONG JING MICRO-ELECTRONICS CO., LTD.

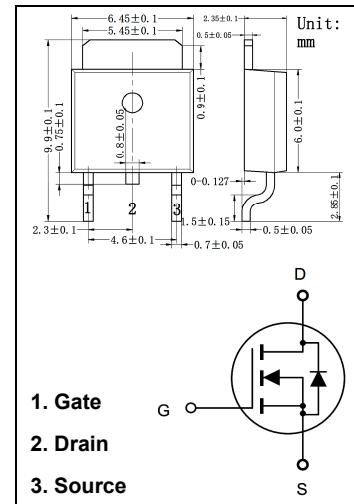
## TO-252 Plastic-Encapsulate MOSFETs

### LJU630N

N-Channel Enhancement Mode Field Effect Transistor

#### Features

- 200V, 7.5A,  $R_{DS(ON)} = 0.35 \Omega$  @  $V_{GS} = 10V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- Lead free product is acquired.



#### Maximum Ratings ( $T_a=25^\circ C$ unless otherwise specified)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source voltage	200	V
$V_{GS}$	Gate-Source voltage	$\pm 20$	
$I_D$	Drain Current	7.5	A
$I_{DM}$	Pulsed Drain Current <sup>1)</sup>	30	
$P_D$	Maximum Power Dissipation @ $T_c = 25^\circ C$ - Derate above $25^\circ C$	54	W
		0.43	$W/\text{ }^\circ C$
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$

#### Thermal Characteristics

Symbol	Parameter	Value	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Case	2.3	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Ambient	50	$^\circ C/W$

## Electrical Characteristics ( $T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$	200			V
$I_{\text{DS}}^{\text{SS}}$	Zero Gate Voltage Drain Current	$V_{DS} = 160\text{V}$ , $V_{GS} = 0\text{V}$			25	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-body Leakage current	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
<b>On Characteristics <sup>2)</sup></b>						
$V_{GS(\text{th})}$	Gate-Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	1.5	1.9	3	V
$R_{DS(\text{on})}$	Drain-Source On-Resistance	$V_{GS} = 10\text{V}$ , $I_D = 3.5\text{A}$		0.28	0.35	$\Omega$
<b>Dynamic Characteristics <sup>3)</sup></b>						
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{V}$ , $I_D = 3.5\text{A}$		4		S
$C_{iss}$	Input Capacitance	$V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$		930		pF
$C_{oss}$	Output Capacitance			130		
$C_{rss}$	Reverse Transfer Capacitance			25		
<b>Switching Characteristics <sup>3)</sup></b>						
$Q_g$	Total Gate Charge	$V_{GS} = 10\text{V}$ , $I_D = 5.9\text{A}$ , $V_{DS} = 160\text{V}$		19	24.7	nC
$Q_{gs}$	Gate-Source Charge			3		
$Q_{gd}$	Gate-Drain Charge			5		
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 100\text{V}$ , $I_D = 5\text{A}$ , $R_G = 50\Omega$ , $V_{GS} = 10\text{V}$		24	48	ns
$t_r$	Rise Time			15	30	
$t_{d(off)}$	Turn-Off Delay Time			116	232	
$t_f$	Fall Time			25	50	
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Drain-Source Diode Forward Current				7.5	A
$V_{SD}$	Drain-Source Diode Forward Voltage <sup>2)</sup>	$V_{GS} = 0\text{V}$ , $I_s = 7.5\text{A}$			1.5	V

**Note:**

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Device Mounted on FR4 Board,  $t < 10$  sec.
3. Pulse Test: Pulse Width  $< 300\mu\text{s}$ , Duty Cycle  $< 2\%$ .
4. Guaranteed by design, not subject to production testing.

## Typical Characteristics

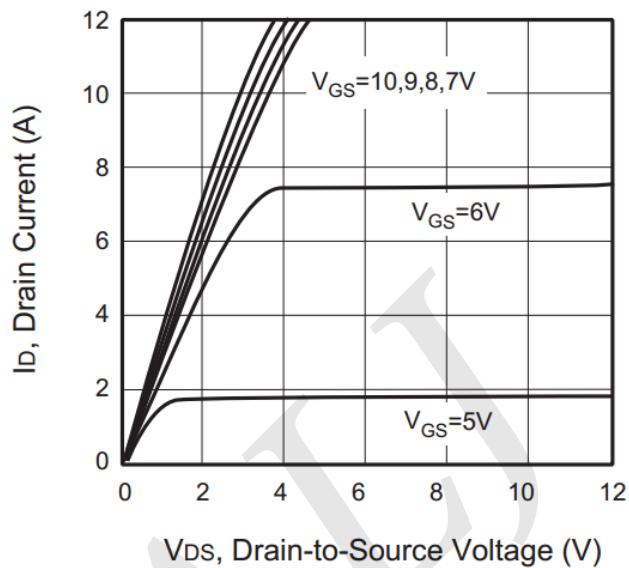


Figure 1. Output Characteristics

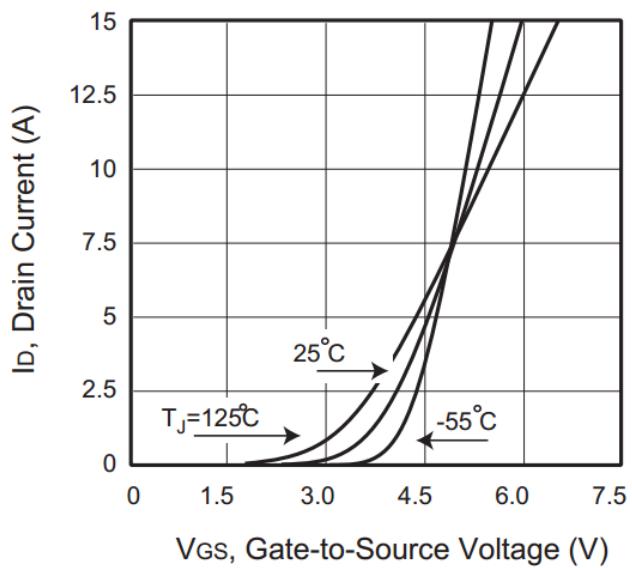


Figure 2. Transfer Characteristics

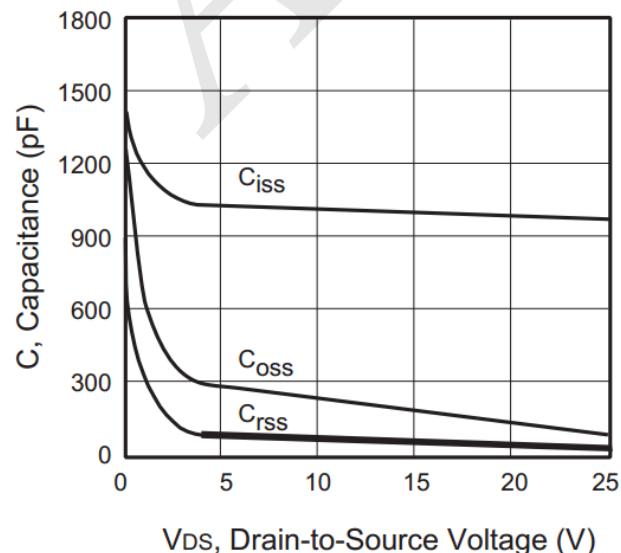


Figure 3. Capacitance

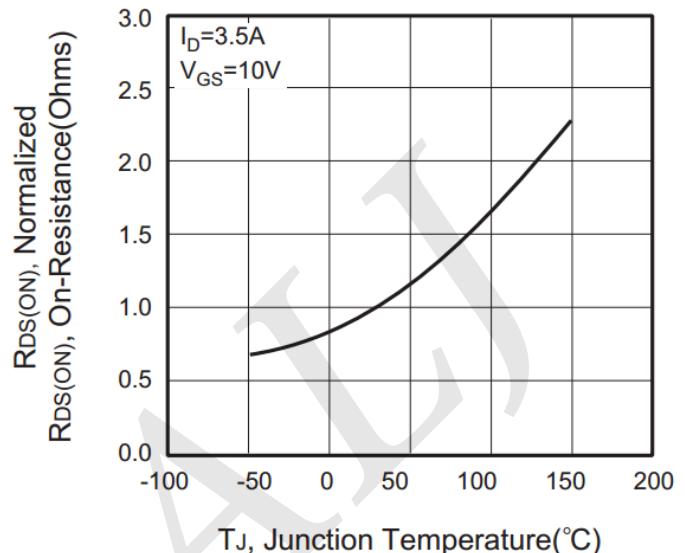


Figure 4. On-Resistance Variation with Temperature

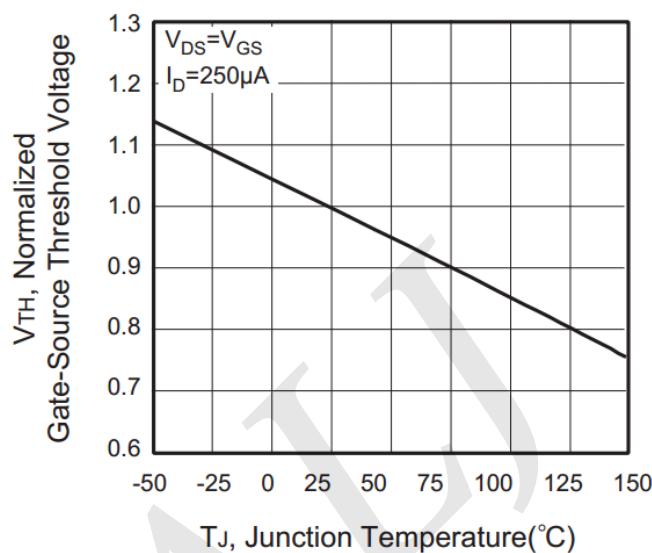


Figure 5. Gate Threshold Variation with Temperature

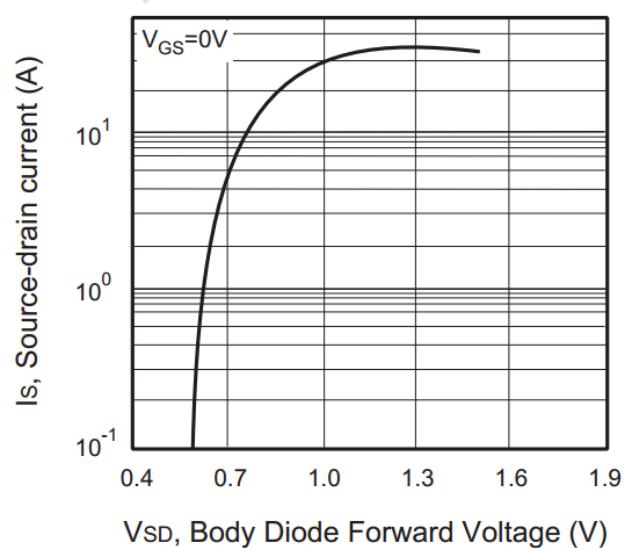


Figure 6. Body Diode Forward Voltage Variation with Source Current

## Typical Characteristics (Cont.)

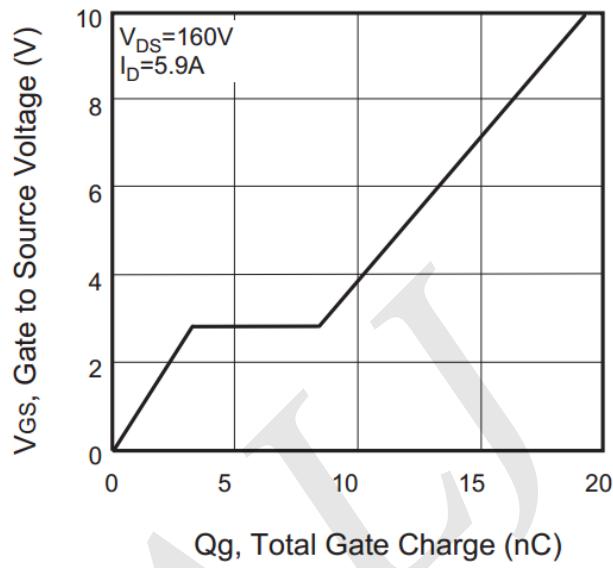


Figure 7. Gate Charge

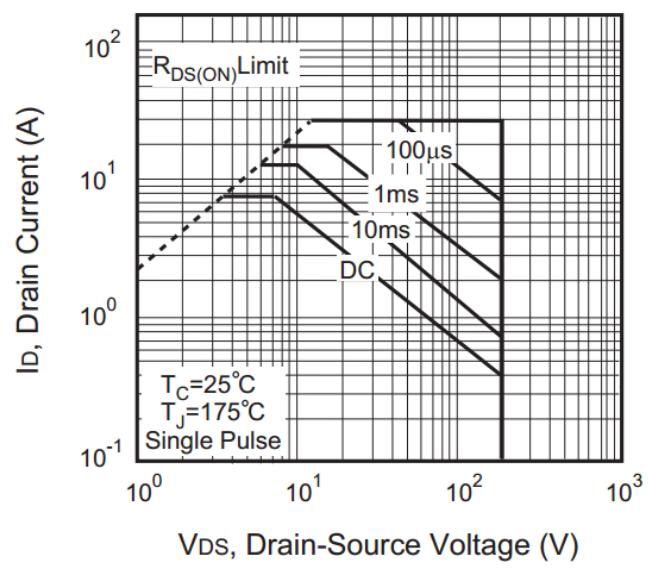


Figure 8. Maximum Safe Operating Area

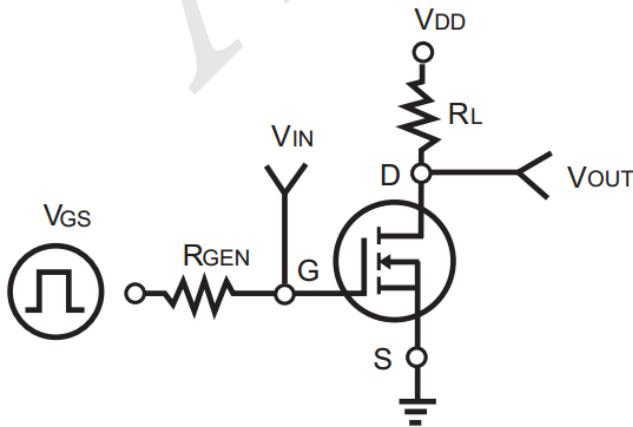


Figure 9. Switching Test Circuit

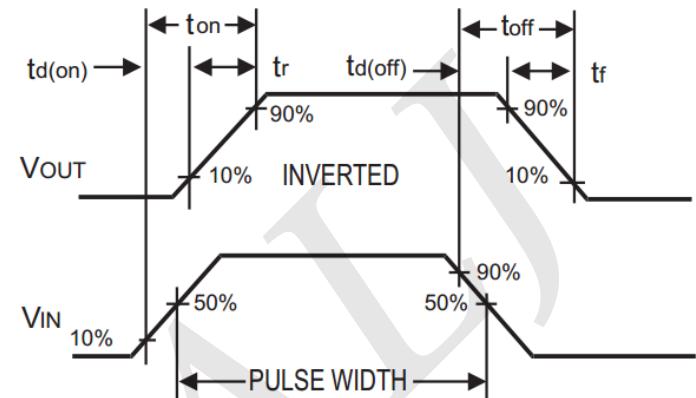


Figure 10. Switching Waveforms

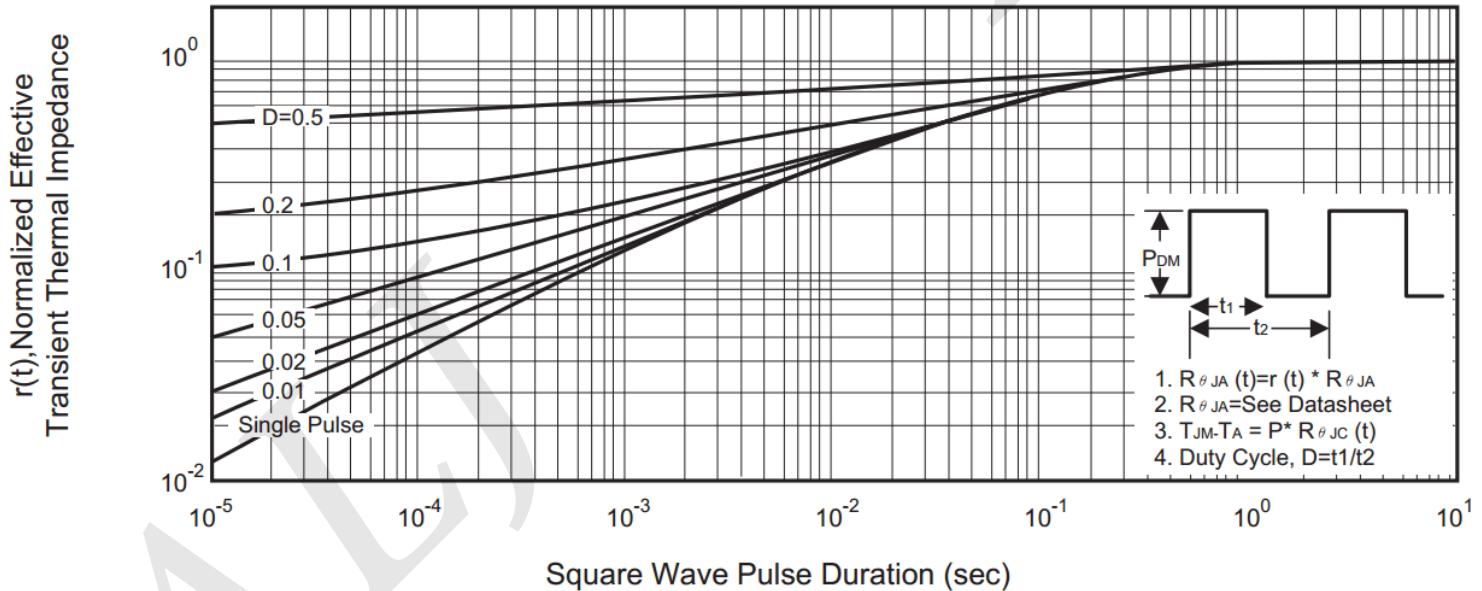


Figure 11. Normalized Thermal Transient Impedance Curve